



CERTIFICATE OF ACCREDITATION

The ANSI National Accreditation Board

Hereby attests that

iTest, Inc.

**1983 Concourse Drive
San Jose, CA 95131**

(and satellite location as listed on the scope)

Fulfills the requirements of

ISO/IEC 17025:2017

In the field of

TESTING

This certificate is valid only when accompanied by a current scope of accreditation document.
The current scope of accreditation can be verified at www.anab.org.

Jason Stine, Vice President

Expiry Date: 08 December 2027

Certificate Number: AT-2534



This laboratory is accredited in accordance with the recognized International Standard ISO/IEC 17025:2017.
This accreditation demonstrates technical competence for a defined scope and the operation of a laboratory
quality management system (refer to joint ISO-ILAC-IAF Communiqué dated April 2017).

SCOPE OF ACCREDITATION TO ISO/IEC 17025:2017

iTest, Inc.

1983 Concourse Dr.
San Jose, CA 95131

Rabbi-ul Islam, QA team
rabbi.islam@itestinc.com (408) 348-9125
www.itestinc.com

TRESTING

ISO/IEC 17025 Accreditation Granted: **08 December 2025**

Certificate Number: **AT-2354** Certificate Expiry Date: **08 December 2027**

Electrical

Specific Tests and/or Properties Measured	Specification, Standard, Method, or Test Technique	Items, Materials or Product Tested	Key Equipment or Technology
Delay Measurements-Measure and Generate	Mil-Std 883 Method 3003.1, Customer-Supplied Specifications	Integrated Circuits	V93000 with Digital Cards and/or Customer-supplied software
Power Supply Current-Measure and Generate	Mil-Std 883 Method 3003.1, Customer-Supplied Specifications	Integrated Circuits	V93000 with DC Scale Cards and/or Customer-supplied software
High Level Output Voltage-Measure and Generate	Mil-Std 883 Method 3003.1, Customer-Supplied Specifications	Integrated Circuits	V93000 with DC Scale Cards and/or Customer-supplied software
Low Level Output Voltage-Measure and Generate	Mil-Std 883 Method 3003.1, Customer-Supplied Specifications	Integrated Circuits	V93000 with DC Scale Cards and/or Customer-supplied software
Functional Testing	Mil-Std 883 Method 3003.1, Customer-Supplied Specifications	Integrated Circuits	V93000 and/or Customer-supplied software
RF Stimulus and Measure	Customer-Supplied Specifications	Integrated Circuits	V93000 with Wave Scale & Port Scale RF Card and/or Customer-supplied software
Waveform Generate and Measure	Customer-Supplied Specifications	Integrated Circuits	V93000 with Wave Scale MX Card and Multi-Band AV8+ and/or Customer-supplied software

Services performed at satellite location

43174 Osgood Road
Fremont, CA 94539
Rabbi-ul Islam
rabbi.islam@itestinc.com (408) 418-1390
www.itestinc.com

Environmental

Specific Tests and/or Properties Measured	Specification, Standard, Method, or Test Technique	Items, Materials or Product Tested	Key Equipment or Technology
Early Life Failure Rate (ELFR)	AEC-Q100-008, JESD22 A108	Integrated Circuits	Burn-In System
Moisture/Reflow Sensitivity Classification for Non-Hermetic Surface Mount Devices (Precondition)	AEC-Q100#A1, J-STD-020	Integrated Circuits	Temperature Humidity Chamber Reflow Chamber
Steady-State Temperature-Humidity Bias Life Test	AEC-Q100#A2, JESD22 A101	Integrated Circuits	Temperature Humidity Chamber
Accelerated Moisture Resistance - Unbiased Autoclave	AEC-Q100#A3, JESD22 A102	Integrated Circuits	HAST Chamber
High Temperature Storage Life	AEC-Q100#A6, JESD22 A103	Integrated Circuits	Temperature Chamber
Temperature Cycling	AEC-Q100#A4, JESD22 A104	Integrated Circuits	Temperature Cycle Chamber
Power and Temperature Cycling	AEC-Q100#A5, JESD22 A105	Integrated Circuits	Power Temperature Cycle Chamber
High Temperature Operating Life	AEC-Q100#B1, JESD22 A108	Integrated Circuits	Burn-In System
Highly Accelerated Temperature and Humidity Stress Test (HAST)	AEC-Q100#A2, JESD22 A110	Integrated Circuits	HAST Chamber
Accelerated Moisture Resistance - Unbiased HAST	AEC-Q100#A3, JESD22 A118	Integrated Circuits	HAST Chamber



Jason Stine, Vice President